Docket No.

245651US2

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yoshio TAKAMI

SERIAL NO:

NEW APPLICATION

GAU:

FILED:

**HEREWITH** 

**EXAMINER:** 

FOR:

METHOD AND APPARATUS FOR FORMING SUBSTRATE FOR SEMICONDUCTOR OR THE LIKE

## **INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

### **CERTIFICATION**

- Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

### DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

C. Irvin McClelland Registration Number 21,124

Customer Number

22850

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 05/03) DOCKET NO.: 245651US2

page <u>1</u> of <u>1</u>

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yoshio TAKAMI

SERIAL NO.: New Application

FILED: Herewith

FOR: METHOD AND APPARATUS FOR FORMING SUBSTRATE FOR

SEMICONDUCTOR OR THE LIKE

# **STATEMENT OF RELEVANCY**

# Reference AW on Form PTO-1449:

This document is disclosed in the body of a specification.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO.		SERIAL NO.		
(Modified)			245651US2		NEW APPLICATION			
				APPLICANT				
LIST OF REFERENCES CITED BY APPLICANT			Yoshio TAKAMI					
				FILING DATE		GROUP		
			HEREWITH					
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	АН							
	AI							
	AJ							
	AK						:	
	AL	<u> </u>						
	AM							
	AN				·			
			FC	REIGN PATENT DOCUMENTS			,	
	_	DOCUMENT NUMBER	DATE	COUNTRY	COUNTRY		TRANSLATION YES NO	
	AO							
	AP					<u> </u>		
	AQ			·		ļ		
	AR							
	AS					<u> </u>		
	AT					<u> </u>		
	AU			1	•	<b></b>		
	AV	<u>,</u>	<u> </u>	<u> </u>		<u> </u>		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW	Mutsuko HATANO, et al., "Excimer laser-induced temperature field in melting and resolidification of silicon thin films", JOURNAL OF APPLIED PHYSICS, Vol. 87, No. 1, January 1, 2000, pp.36-43						
	AX							
	AY							
	AZ				Add	litional Ref	erences sheet(s) attached	
Examiner					Date Co	Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								